Se	arcn No	otes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/567,824	TAKAHASHI ET AL.
Examiner	Art Unit
RuiMeng Hu	2618

SEARCHED				
Class	Subclass	Date	Examiner	
			•	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
			·	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (USPAT, USPGPUB, EPO, JPO, DERWENT, IBM_TDB) - See Search History Printout	6/23/2007	RH		
		•		
· · · · · · · · · · · · · · · · · · ·				
<del> </del>				